

检测报告

Test Report



报告编号 A2240683965101001E
Report No. A2240683965101001E

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报告抬头公司名称 如皋市大昌电子有限公司
Company Name RUGAO DACHANG ELECTRONICS CO., LTD
shown on Report
地 址 江苏省如皋市柴湾工业园区
Address CHAIWAN INDUSTRIAL PARK, RUGAO, JIANGSU, CHINA

以下测试之样品及样品信息由申请者提供并确认

The following sample(s) and sample information was/were submitted and identified by/on the behalf of the applicant

样品名称 二极管
Sample Name Diode
样品型号 SMA
Model No. SMA
样品接收日期 2024.11.04
Sample Received Date Nov. 4, 2024
样品检测日期 2024.11.04-2024.11.07
Testing Period Nov. 4, 2024 to Nov. 7, 2024

检测要求 根据客户要求, 对所提交样品中的氟(F), 氯(Cl), 溴(Br), 碘(I)进行测试。
Test Requested As specified by client, to test Fluorine (F), Chlorine (Cl), Bromine (Br), Iodine (I) in the submitted sample(s).

检测依据/检测结果 请参见下页。
Test Method/Test Result(s) Please refer to the following page(s).



陈凯敏

陈凯敏
实验室经理 Lab Manager

日期
Date

2024.11.07

No. R794241968

上海市闵行区万芳路1351号

No.1351, Wanfang Road, Minhang District, Shanghai, China

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检测依据 Test Method

测试项目 Test Item(s)	测试方法 Test Method	测试仪器 Measured Equipment(s)
氟 Fluorine (F)	EN 14582:2016	IC
氯 Chlorine (Cl)	EN 14582:2016	IC
溴 Bromine (Br)	EN 14582:2016	IC
碘 Iodine (I)	EN 14582:2016	IC

检测结果 Test Result(s)

测试项目 Tested Item(s)	结果 Result	方法检出限 MDL
	001	
氟 Fluorine (F)	N.D.	10 mg/kg
氯 Chlorine (Cl)	N.D.	10 mg/kg
溴 Bromine (Br)	3876 mg/kg	10 mg/kg
碘 Iodine (I)	N.D.	10 mg/kg

样品/部位描述 Sample/Part Description

序号 No.	CTI样品ID CTI Sample ID	描述 Description
1	001	电子元器件（整体测试） Electronic components(Tested as a whole)

备注：-按照目前手段，样品无法进一步拆分，样品整体测试，测试结果不代表整体测试样品中任何一种单一材质的含量。

-N.D. = 未检出（小于方法检出限）

-mg/kg = ppm = 百万分之一

Remark: -The sample(s) was tested as a whole, because it's impossible to disassemble or separate it by current equipment and technology. The result(s) shown on this report may be different from the content of any homogeneous material.

-MDL = Method Detection Limit

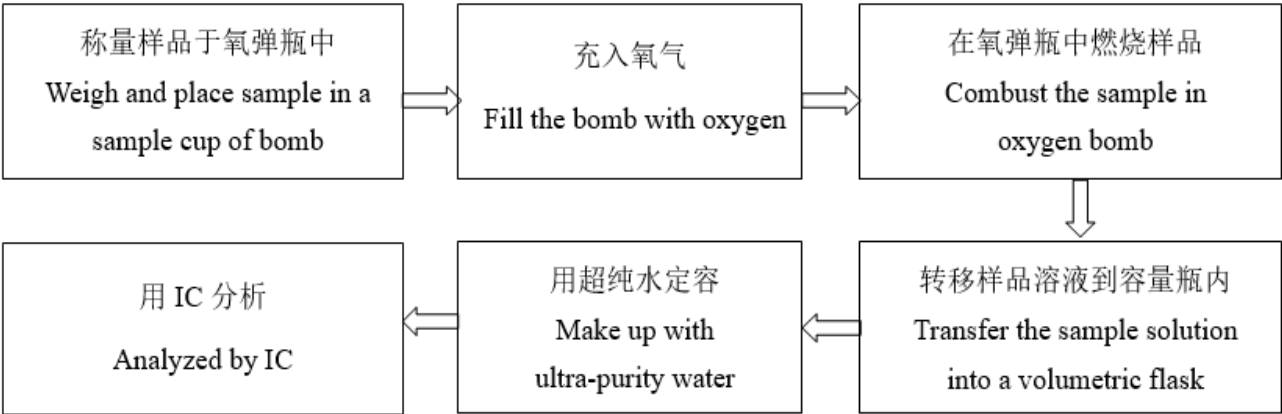
-N.D. = Not Detected (<MDL)

-mg/kg = ppm = parts per million

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检测流程 Test Process

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样品图片 Photo(s) of the sample(s)



声明Statement:

1. 检测报告无批准人签字、“专用章”及报告骑缝章无效;
This report is considered invalid without approved signature, special seal and the seal on the perforation;
2. 报告抬头公司名称及地址、样品及样品信息由申请者提供, 申请者应对其真实性负责, CTI未核实其真实性;
The Company Name shown on Report and Address, the sample(s) and sample information was/were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified;
3. 本报告检测结果仅对受测样品负责;
The result(s) shown in this report refer(s) only to the sample(s) tested;
4. 除非另有说明, 报告参照ILAC-G8:09/2019 / CNAS-GL015:2022使用简单接受(w=0)二元判定规则进行符合性判定;
Unless otherwise stated, the decision rule for conformity reporting is based on Binary Statement for Simple Acceptance Rule (w=0) stated in ILAC-G8:09/2019 / CNAS-GL015:2022;
5. 未经CTI书面同意, 不得部分复制本报告;
Without written approval of CTI, this report can't be reproduced except in full;
6. 如检测报告中的英文内容与中文内容有差异, 以中文为准。
In case of any discrepancy between the English version and Chinese version of the testing reports (if generated), the Chinese version shall prevail.

报告结束

*** End of report ***

附录Appendix

客户参考信息Client Reference Information

贴片二极管 (Surface Mount Diode) SMB、SMC、SMA-FL、SMA-W、SOD123、SOD323、SOD123FL、DO213AA、T0系列 (T0 series) IT0220、T0252、T0263、SOT82、T0247、T0277B、T0220F、轴向二极管 (Axial diode) R1、A405、DO15、DO15L、DO27、R6、桥堆 (Bridge) D5、GBL、GBU、KBL、KBU、KBJ、KBP、KBK、ABS、DB、DBS、MB、MBS、MBLS、FBS、高压二极管系列 (HIGH-VOLTAGE DIODES)

声明Statement:

1. 附录内容由申请者提供，申请者应对其真实性负责，CTI未核实其真实性。
The Appendix Information was/were provided by the applicant who should be responsible for the authenticity which CTI hasn't verified.
2. 附录内容为A2240683965101001E报告的补充。
The Appendix Information is/are the supplement(s) for the Report A2240683965101001E.

